A1250

## Hall-Effect Latch / Bipolar Switch

## FEATURES AND BENEFITS

- AEC-Q100 automotive qualified
- Quality managed (QM), ISO 26262:2011 compliant
- High-speed 4-phase chopper stabilization
- Low operating voltage down to 3 V
- High sensitivity
- Stable switchpoints
- Robust EMC


## PACKAGES:

3-Pin SOT23W<br>(suffix LH)<br>

3-Pin SIP (suffix UA)


## DESCRIPTION

The A1250 Hall-effect sensor IC is a temperature-stable, stress-resistant bipolar switch. This device is the most sensitive Hall-effect device in the Allegro ${ }^{\text {TM }}$ bipolar switch family and is intended for ring-magnet sensing. Superior high-temperature performance is made possible through an Allegro dynamic offset cancellation that utilizes chopper stabilization. This method reduces the offset voltage normally caused by device overmolding, temperature dependencies, and thermal stress.

The A1250 includes the following on a single silicon chip: a voltage regulator, Hall-voltage generator, small-signal amplifier, chopper stabilization, Schmitt trigger, and a short-circuit-protected open-drain output. Advanced BiCMOS wafer fabrication processing takes advantage of low-voltage requirements, component matching, very low input-offset errors, and small component geometries.
The A1250 Hall-effect bipolar switch turns on in a south polarity magnetic field of sufficient strength and switches off in a north polarity magnetic field of sufficient strength. Because the output state is not defined if the magnetic field is diminished or removed, to ensure that the device switches, Allegro recommends using magnets of both polarities and of sufficient strength in the application.

The A1250 is rated for operation in the ambient temperature range $\mathrm{L},-40^{\circ} \mathrm{C}$ to $150^{\circ} \mathrm{C}$. Two package styles provide magnetically optimized solutions for most applications. Each package is lead $(\mathrm{Pb})$ free version, with $100 \%$ matte-tin-plated leadframe.


## SPECIFICATIONS

## SELECTION GUIDE

| Part Number | Packing [1] | Mounting | Ambient, $T_{\mathbf{A}}$ <br> $\left({ }^{\circ} \mathrm{C}\right)$ |
| :---: | :---: | :---: | :---: |
| A1250LLHLT-T | 7-in. reel, 3,000 pieces/reel | Surface mount | -40 to 150 |
| A1250LLHLX-T | 13-in. reel, 10,000 pieces/reel | Surface mount |  |
| A1250LUA-T | Bulk, 500 pieces/bag | SIP through hole |  |


${ }^{[1]}$ Contact Allegro for additional packing options.

## ABSOLUTE MAXIMUM RATINGS

| Characteristic | Symbol | Notes | Rating | Unit ${ }^{[2]}$ |
| :--- | :---: | :---: | :---: | :---: |
| Forward Supply Voltage ${ }^{[3]}$ | $\mathrm{V}_{\mathrm{CC}}$ |  | 28 |  |
| Reverse Supply Voltage ${ }^{[3]}$ | $\mathrm{V}_{\text {RCC }}$ |  | V |  |
| Output Off Voltage ${ }^{[3]}$ | $\mathrm{V}_{\text {OUT }}$ |  | -18 | V |
| Reverse Output Voltage ${ }^{[3]}$ | $\mathrm{V}_{\text {ROUT }}$ |  | 28 | V |
| Output Current | $\mathrm{I}_{\text {OUTSINK }}$ |  | -0.6 | V |
| Reverse Output Current | $\mathrm{I}_{\text {ROUT }}$ |  | Internally limited | A |
| Magnetic Flux Density ${ }^{[4]}$ | B |  | -10 | mA |
| Operating Ambient Temperature | $\mathrm{T}_{\mathrm{A}}$ | Range L | Unlimited | G |
| Maximum Junction Temperature | $\mathrm{T}_{\mathrm{J}(\max )}$ |  | -40 to 150 | ${ }^{\circ} \mathrm{C}$ |
| Storage Temperature | $\mathrm{T}_{\text {stg }}$ |  | -65 to 170 | ${ }^{\circ} \mathrm{C}$ |

[2] 1 G (gauss) $=0.1 \mathrm{mT}$ (millitesla).
[3] This rating does not apply to extremely short voltage transients such as Load Dump and/or ESD. Those events have individual ratings, specific to the respective transient voltage event.
${ }^{\text {[4] }}$ Guaranteed by design.

## PINOUT DIAGRAMS AND TERMINAL LIST TABLE



Package LH


Package UA

Terminal List Table

| Name | Number |  | Function |
| :---: | :---: | :---: | :--- |
|  | Package <br> LH | Package <br> UA |  |
| VCC | 1 | 1 |  |
| VOUT | 2 | 3 | Device output |
| GND | 3 | 2 | Ground |

OPERATING CHARACTERISTICS: Valid at $\mathrm{T}_{\mathrm{A}}=-40^{\circ} \mathrm{C}$ to $150^{\circ} \mathrm{C}, \mathrm{C}_{\text {BYPASS }}=0.1 \mu \mathrm{~F}$, unless otherwise noted

| Characteristic | Symbol | Test Conditions | Min. | Typ. | Max. | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| ELECTRICAL CHARACTERISTICS |  |  |  |  |  |  |
| Supply Voltage | $\mathrm{V}_{\mathrm{CC}}$ | Operating $\mathrm{T}_{\mathrm{J}}<165^{\circ} \mathrm{C}$ | 3.0 | - | 24 | V |
| Output Leakage Current | Ioutoff | $\mathrm{V}_{\text {OUT }}=24 \mathrm{~V}, \mathrm{~B}<\mathrm{B}_{\mathrm{RP}}$ | - | - | 10 | $\mu \mathrm{A}$ |
| Output On Voltage | $\mathrm{V}_{\text {OUT(SAT) }}$ | $\mathrm{I}_{\text {OUT }}=20 \mathrm{~mA}, \mathrm{~B}>\mathrm{B}_{\text {OP }}$ | - | - | 500 | mV |
| Output Current Limit | $\mathrm{I}_{\text {OM }}$ | $\mathrm{B}>\mathrm{B}_{\mathrm{OP}}$ | 30 | - | 60 | mA |
| Power-On Time | $\mathrm{t}_{\mathrm{PO}}$ | $\mathrm{V}_{\mathrm{CC}}>3.0 \mathrm{~V}$ | - | - | 25 | $\mu \mathrm{s}$ |
| Chopping Frequency | $\mathrm{f}_{\mathrm{c}}$ |  | - | 160 | - | kHz |
| Output Rise Time ${ }^{[1]}$ | $\mathrm{t}_{\mathrm{r}}$ | $\mathrm{R}_{\text {LOAD }}=820 \Omega, \mathrm{C}_{\mathrm{S}}=20 \mathrm{pF}$ | - | - | 2 | $\mu \mathrm{s}$ |
| Output Fall Time ${ }^{[1]}$ | $\mathrm{t}_{\mathrm{f}}$ | $\mathrm{R}_{\text {LOAD }}=820 \Omega, \mathrm{C}_{\mathrm{S}}=20 \mathrm{pF}$ | - | - | 2 | $\mu \mathrm{s}$ |
| Supply Current | $\mathrm{I}_{\mathrm{CCON}}$ | $\mathrm{B}>\mathrm{B}_{\mathrm{OP}}$ | - | - | 4 | mA |
|  | $\mathrm{I}_{\text {CCOFF }}$ | $\mathrm{B}<\mathrm{B}_{\mathrm{RP}}$ | - | - | 4 | mA |
| Reverse Battery Current | $\mathrm{I}_{\text {RCC }}$ | $\mathrm{V}_{\mathrm{RCC}}=-18 \mathrm{~V}$ | - | - | -2 | mA |
| Supply Zener Clamp Voltage | $\mathrm{V}_{\mathrm{Z}}$ | $\mathrm{I}_{\mathrm{CC}}=6.5 \mathrm{~mA}, \mathrm{~T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ | 28 | - | - | V |
| Supply Zener Current | $\mathrm{I}_{\mathrm{z}}$ | $\mathrm{V}_{\mathrm{CC}}=28 \mathrm{~V}$ | - | - | 7 | mA |
| MAGNETIC CHARACTERISTICS [2]: Valid at $\mathrm{T}_{\mathrm{A}}=-40^{\circ} \mathrm{C}$ to $150^{\circ} \mathrm{C}, \mathrm{T}_{J} \leq \mathrm{T}_{J}(\mathrm{max})$, unless otherwise noted |  |  |  |  |  |  |
| Operate Point | $\mathrm{B}_{\mathrm{OP}}$ |  | -10 | 5 | 25 | G |
| Release Point | $\mathrm{B}_{\mathrm{RP}}$ |  | -25 | -5 | 10 | G |
| Hysteresis | $\mathrm{B}_{\mathrm{HYS}}$ |  | 5 | 10 | 25 | G |

${ }^{[1]}$ Guaranteed by design.
${ }^{[2]}$ Magnetic flux density, B, is indicated as negative value for north-polarity fields, and positive for south-polarity fields.

THERMAL CHARACTERISTICS: May require derating at maximum conditions; see application information

| Characteristic | Symbol | Test Conditions* | Value | Units |
| :---: | :---: | :---: | :---: | :---: |
| Package Thermal Resistance | $\mathrm{R}_{\theta \mathrm{JA}}$ | Package LH, 1-layer PCB with copper limited to solder pads | 228 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
|  |  | Package LH, 2-layer PCB with 0.463 in. ${ }^{2}$ of copper area each side connected by thermal vias | 110 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
|  |  | Package UA, 1-layer PCB with copper limited to solder pads | 165 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |

*Additional thermal information available on Allegro Web site.


Power Dissipation versus Ambient Temperature


## CHARACTERISTIC PERFORMANCE DATA




## FUNCTIONAL DESCRIPTION

The output of this device switches low (turns on) when a magnetic field perpendicular to the Hall sensor IC exceeds the operate point threshold, $\mathrm{B}_{\mathrm{OP}}$. After turn-on, the output voltage is $\mathrm{V}_{\text {OUT(SAT) }}$. The output transistor is capable of sinking current up to the short circuit current limit $\mathrm{I}_{\mathrm{OM}}$, which is a minimum of 30 mA . When the magnetic field is reduced below the release point, $B_{R P}$, the device output goes high (turns off). The difference in the magnetic operate and release points is the hysteresis, $\mathrm{B}_{\mathrm{HYS}}$, of the device. This built-in hysteresis allows clean switching of the output even in the presence of external mechanical vibration and electrical noise.

Given the magnetic parameter specifications (refer to Magnetic Characteristics table), bipolar switches will operate in one of three modes, depending on switchpoints. For typical values of $\mathrm{B}_{\mathrm{OP}}$ and $\mathrm{B}_{\mathrm{RP}}$, the device will operate as a latch, as shown in figure 1a. Note that, when the magnetic flux density exceeds a switchpoint, the output will retain its state when the magnetic field is removed. The other two modes of operation are the uni-
polar switch and the negative switch, shown in panels 1 b and 1 c , respectively. The unipolar switch type operates only in a south polarity field, and will switch to the high state if the magnetic field is removed. The negative switch operates only in a north polarity field, and will switch to the low state if the magnetic field is removed.

Individual bipolar switch devices exhibit any one of the three switching behaviors: latch, unipolar, or negative switch. Because these devices are not guaranteed to behave as latches, magnetic fields of sufficient magnitude and alternate polarity are required to ensure output switching.

Powering up the device in the hysteresis band, that is in a magnetic field less than $\mathrm{B}_{\mathrm{OP}}$ and higher than $\mathrm{B}_{\mathrm{RP}}$, allows an indeterminate output state. Note that this hysteresis band encompasses zero magnetic field on devices that exhibit latch behaviors. The correct state is determined after the first magnetic excursion beyond $\mathrm{B}_{\mathrm{OP}}$ or $\mathrm{B}_{\mathrm{RP}}$.


Figure 1: Bipolar Device Output Switching Modes
These behaviors can be exhibited when using a circuit such as that shown in figure 1. Panel A displays the hysteresis when a device exhibits latch mode (note that the $B_{H Y S}$ band incorporates $B=0$ ), panel $B$ shows unipolar switch behavior (the $B_{H Y S}$ band is more positive than $B=0$ ), and panel $C$ shows negative switch behavior (the $B_{H Y S}$ band is more negative than $B=0$ ). Bipolar devices, such as the $A 1250$, can operate in any of the three modes.

## APPLICATION INFORMATION

## Functional Safety

The A1250 complies with the international standard for automotive functional safety, ISO 26262:2011, as a Quality Managed (QM) product. The device is classified as a SEooC (Safety Element out of Context) and can be easily integrated into safety-critical systems requiring higher ASIL ratings that incorporate external diagnostics or use measures such as redundancy. Safety documentation will be provided to support and guide the integration process. For further information, contact your local Allegro field applications engineer or sales representative.

## Chopper Stabilization Technique

When using Hall-effect technology, a limiting factor for switchpoint accuracy is the small signal voltage developed across the Hall element. This voltage is disproportionally small relative to the offset that can be produced at the output of the Hall sensor IC. This makes it difficult to process the signal while maintaining an accurate, reliable output over the specified operating temperature and voltage ranges. Chopper stabilization is a unique approach used to minimize Hall offset on the chip. Allegro employs a technique to remove key sources of the output drift induced by thermal and mechanical stresses. This offset reduction technique is based on a signal modulation-demodulation process. The undesired offset signal is separated from the magnetic fieldinduced signal in the frequency domain, through modulation. The subsequent demodulation acts as a modulation process for the offset, causing the magnetic field-induced signal to recover its original spectrum at base band, while the DC offset becomes a high-frequency signal. The magnetic-sourced signal then can


Figure 2: Typical Application Circuit
pass through a low-pass filter, while the modulated DC offset is suppressed. In addition to the removal of the thermal and stress related offset, this novel technique also reduces the amount of thermal noise in the Hall sensor IC while completely removing the modulated residue resulting from the chopper operation. The chopper stabilization technique uses a high frequency sampling clock. For demodulation process, a sample and hold technique is used. This high-frequency operation allows a greater sampling rate, which results in higher accuracy and faster signal-processing capability. This approach desensitizes the chip to the effects of thermal and mechanical stresses, and produces devices that have extremely stable quiescent Hall output voltages and precise recoverability after temperature cycling. This technique is made possible through the use of a BiCMOS process, which allows the use of low-offset, low-noise amplifiers in combination with highdensity logic integration and sample-and-hold circuits.


Figure 3: Concept of Chopper Stabilization Technique

## POWER DERATING

The device must be operated below the maximum junction temperature of the device, $\mathrm{T}_{\mathrm{J}(\max )}$. Under certain combinations of peak conditions, reliable operation may require derating supplied power or improving the heat dissipation properties of the application. This section presents a procedure for correlating factors affecting operating $\mathrm{T}_{\mathrm{J}}$. (Thermal data is also available on the Allegro MicroSystems website.)
The Package Thermal Resistance, $R_{\theta J A}$, is a figure of merit summarizing the ability of the application and the device to dissipate heat from the junction (die), through all paths to the ambient air. Its primary component is the Effective Thermal Conductivity, K , of the printed circuit board, including adjacent devices and traces. Radiation from the die through the device case, $R_{\theta \mathrm{JC}}$, is relatively small component of $R_{\theta J A}$. Ambient air temperature, $\mathrm{T}_{\mathrm{A}}$, and air motion are significant external factors, damped by overmolding.
The effect of varying power levels (Power Dissipation, $\mathrm{P}_{\mathrm{D}}$ ), can be estimated. The following formulas represent the fundamental relationships used to estimate $\mathrm{T}_{\mathrm{J}}$, at $\mathrm{P}_{\mathrm{D}}$.

$$
\begin{gather*}
P_{D}=V_{I N} \times I_{I N}  \tag{1}\\
\Delta T=P_{D} \times R_{\theta J A}  \tag{2}\\
T_{J}=T_{A}+\Delta T \tag{3}
\end{gather*}
$$

For example, given common conditions such as: $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$, $\mathrm{V}_{\mathrm{IN}}=12 \mathrm{~V}, \mathrm{I}_{\mathrm{IN}}=4 \mathrm{~mA}$, and $\mathrm{R}_{\theta \mathrm{JA}}=140^{\circ} \mathrm{C} / \mathrm{W}$, then:

$$
\begin{gathered}
P_{D}=V_{I N} \times I_{I N}=12 \mathrm{~V} \times 4 \mathrm{~mA}=48 \mathrm{~mW} \\
\Delta T=P_{D} \times R_{\theta J A}=48 \mathrm{~mW} \times 140^{\circ} \mathrm{C} / \mathrm{W}=7^{\circ} \mathrm{C} \\
T_{J}=T_{A}+\Delta T=25^{\circ} \mathrm{C}+7^{\circ} \mathrm{C}=32^{\circ} \mathrm{C}
\end{gathered}
$$

A worst-case estimate, $\mathrm{P}_{\mathrm{D}(\max )}$, represents the maximum allowable power level, without exceeding $\mathrm{T}_{\mathrm{J}(\max )}$, at a selected $\mathrm{R}_{\theta \mathrm{JA}}$ and $\mathrm{T}_{\mathrm{A}}$.
Example: Reliability for $\mathrm{V}_{\mathrm{CC}}$ at $\mathrm{T}_{\mathrm{A}}=150^{\circ} \mathrm{C}$, package UA , using a single-layer PCB.
Observe the worst-case ratings for the device, specifically:
$\mathrm{R}_{\theta \mathrm{JA}}=165^{\circ} \mathrm{C} / \mathrm{W}, \mathrm{T}_{\mathrm{J}(\max )}=165^{\circ} \mathrm{C}, \mathrm{V}_{\mathrm{CC}(\max )}=24 \mathrm{~V}$, and $\mathrm{I}_{\mathrm{CC}(\max )}=4 \mathrm{~mA}$.
Calculate the maximum allowable power level, $\mathrm{P}_{\mathrm{D}(\max )}$. First, invert equation 3 :

$$
\Delta T_{\max }=T_{J(\max )}-T_{A}=165^{\circ} \mathrm{C}-150^{\circ} \mathrm{C}=15^{\circ} \mathrm{C}
$$

This provides the allowable increase to $\mathrm{T}_{\mathrm{J}}$ resulting from internal power dissipation. Then, invert equation 2 :

$$
P_{D(\max )}=\Delta T_{\max } \div R_{\theta J A}=15^{\circ} \mathrm{C} \div 165^{\circ} \mathrm{C} / \mathrm{W}=91 \mathrm{~mW}
$$

Finally, invert equation 1 with respect to voltage:

$$
V_{C C(e s t)}=P_{D(\max )} \div I_{C C(\max )}=91 \mathrm{~mW} \div 4 m A=23 \mathrm{~V}
$$

The result indicates that, at $\mathrm{T}_{\mathrm{A}}$, the application and device can dissipate adequate amounts of heat at voltages $\leq \mathrm{V}_{\mathrm{CC}(\text { est) }}$.
Compare $\mathrm{V}_{\mathrm{CC}(\text { est })}$ to $\mathrm{V}_{\mathrm{CC}(\max )}$. If $\mathrm{V}_{\mathrm{CC}(\text { est })} \leq \mathrm{V}_{\mathrm{CC}(\max )}$, then reliable operation between $\mathrm{V}_{\mathrm{CC}(\text { est })}$ and $\mathrm{V}_{\mathrm{CC}(\max )}$ requires enhanced $\mathrm{R}_{\text {OJA }}$. If $\mathrm{V}_{\mathrm{CC}(\text { est })} \geq \mathrm{V}_{\mathrm{CC}(\max )}$, then operation between $\mathrm{V}_{\mathrm{CC}(\text { est })}$ and $\mathrm{V}_{\mathrm{CC}(\max )}$ is reliable under these conditions.

## PACKAGE OUTLINE DRAWINGS



Figure 4: Package LH, 3-Pin SOT23W

# For Reference Only - Not for Tooling Use 

(Reference DWG-0000404, Rev. 1)
NOT TO SCALE
Dimensions in millimeters
Dimensions exclusive of mold flash, gate burrs, and dambar protrusions
Exact case and lead configuration at supplier discretion within limits shown


Figure 5: Package UA, 3-Pin SIP

## Revision History

| Number | Date |  |
| :---: | :---: | :--- |
| 1 | March 22, 2012 | Description |
| 2 | October 29,2014 | Corrected tolerance on Package Outline Drawing |
| 3 | February 4, 2015 | Corrected dimension on Package Drawing |
| 4 | September 21, 2015 | Added AEC-Q100 qualification under Features and Benefits |
| 5 | September 26,2017 | Added Functional Safety information; added footnote to Absolute Maximum Ratings table |
| 6 | October 12,2018 | Added footnote to Magnetic Flux Density (page 2); minor editorial updates. |

## Copyright ©2018, Allegro MicroSystems, LLC

Allegro MicroSystems, LLC reserves the right to make, from time to time, such departures from the detail specifications as may be required to permit improvements in the performance, reliability, or manufacturability of its products. Before placing an order, the user is cautioned to verify that the information being relied upon is current.
Allegro's products are not to be used in any devices or systems, including but not limited to life support devices or systems, in which a failure of Allegro's product can reasonably be expected to cause bodily harm.
The information included herein is believed to be accurate and reliable. However, Allegro MicroSystems, LLC assumes no responsibility for its use; nor for any infringement of patents or other rights of third parties which may result from its use.
Copies of this document are considered uncontrolled documents.

For the latest version of this document, visit our website:
www.allegromicro.com

## X-ON Electronics

Largest Supplier of Electrical and Electronic Components
Click to view similar products for Motor/Motion/Ignition Controllers \& Drivers category:
Click to view products by Allegro manufacturer:
Other Similar products are found below :
LV8133JA-ZH LV8169MUTBG LV8774Q-AH LV8860PV-TLM-H MC33931EKR2 MC34GD3000EP FSB50250UTD FSB50550TB2 FSBF15CH60BTH MP6507GR-P MP6508GF MSVCPM2-63-12 MSVGW45-14-2 MSVGW54-14-5 NTE7043 CAT3211MUTAG LA6245P-CL-TLM-E LA6245P-TLM-E LA6565VR-TLM-E LB11650-E LB1694N-E LB1837M-TLM-E LB1845DAZ-XE LC898111AXBMH LC898300XA-MH SS30-TE-L-E STK531-345A-E STK581U3A0D-E STK58AUNP0D-E STK621-068C-E STK621-140C STK621-728S-E STK625-728-E STK672-400B-E STK672-432AN-E STK672-432BN-E STK672-440AN-E STK672-442AN-E AMIS30621AUA FSB50550ASE 26700 LV8161MUTAG LV8281VR-TLM-H LV8702V-TLM-H LV8734VZ-TLM-H LV8773Z-E LV8807QA-MH MC33932EK MCP8024T-H/MP TND027MP-AZ

